

**Notice of References Cited**

Application/Control No.

10/535,133

Applicant(s)/Patent Under  
Reexamination  
WEXLER, ANTHONY S

Examiner

Yelena G. Gakh, Ph.D.

Art Unit

1797

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fuerstenau et al. "Active pixel sensors for mass spectrometry", International Journal of Mass Spectrometry, April 2002, v. 215, pp.101-111
	V	Schmitt et al. "High Resolution Differential Mobility Analysis" 2nd Joint Conference on Point Detection for Chemical and Biological Defense SESSION: Chemical Detection / Identification March 4, 2004: Williamsburg VA <a href="http://nan-engineeringcorp.com/uploads/Point_Detection_-_NanoEngineering.PDF">http://nan-engineeringcorp.com/uploads/Point_Detection_-_NanoEngineering.PDF</a>
	W	Koomen et al. "Oligonucleotide analysis with MALDI-ion-mobility-TOFMS", Anal Bioanal Chem, June 2002, v. 373, pp. 612-617
	X	Zhang et al. "Cross flow ion mobility spectrometry: Theory and initial prototype testing", International Journal of Mass Spectrometry, 2006, v. 258, pp. 13-20

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.